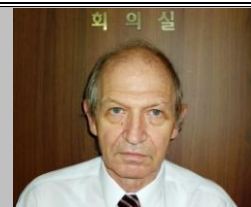


Professional Experience (Job Career)



Total years of experience

40

Organization	Period	Position	Participation in Projects
QM&E company (ltd)	2012 -		Resolving R&D problem with using TRIZ TRIZ education
Samsung Electro-Mechanics (SEMCO), Korea	2007 - 2012	TRIZ expert Principal Engineer	Resolving R&D problem with using TRIZ (more then 50 project), TRIZ education (Eng)
Samsung Advances Insitute of Technology (SAIT), Korea	2002 - 2007	TRIZ expert Senior Manager	Resolving R&D problem with using TRIZ (more then 50 project), TRIZ education (Eng)
Samsung Display Devise (SDI), Korea	1999 - 2002	TRIZ-consultant	Resolving R&D problem with using TRIZ (more then 15 project), TRIZ education (Eng)
Leningrad Union of Electronics Industry "SVETLANA", Russia	1972 - 1999	Chief of laboratory Principal engineer Leading engineer Engineer	R&D works connected with development and mass production of Si Integrated Circuits (IC) and high frequency discrete devices (diodes, transistors and so on). Participation in more then 50 Scientific –Research and Developmental works with using TRIZ in different positions – from linear engineer – technologist, Principle engineer, Chief of laboratory - Project Manager.

TRIZ activity

Leningrad Union of Electronics Industry "SVETLANA", Russia	1972 -1982	Engineer- TRIZ education V.Mitrofanov- chief of Department	20 TRIZ projects
MA TRIZ	2004	Level 4 MA TRIZ	
MA TRIZ	2010 till now	Member of Council of Expertise and Methodology (CEM)	Accreditation of MA TRIZ representatives for attestation to level 1-3
MA TRIZ	2011 till now	Chairman of certification Committee for level 4	Certification of representatives from countries of South-East Asia (Korea, China, Japan and others - Eng)

Most relevant Publications in TRIZ

Title	Journal / Proceedings
V.Leniachine and others: "Hands-on Logic for inventive Problem Solving . TRIZ in Samsung R&D Process",	http://www.triz-journal.com/archives/ 2004

V.Lenyashin , H.J.Kim : Harmful system	TRIZ-fest 2005
V.Leniachine and others: The block diagram of problem solving with TRIZ	http://www.etrina.net/abstracts.htm 2006.
Vasiliy Lenyachin A.Kynin: "The Systematic Study of the Technical Systems Evolution "	TRIZ-fest 2007
V.Lenyashin and others: "TRIZ and innovation culture at Samsung Electro-Mechanics Company"	The Fourth TRIZ Symposium in Japan, 2008 Sept. 10-12, 2008 http://www.osaka-gu.ac.jp/php/nakagawa/TRIZ/eTRIZ/elinksref/eJapanTRIZ-CB/e4thTRIZSymp08/eTRIZSymp2008-Abstracts.pdf

Most relevant Patents (in Samsung – Korea for the last 10 years)

Subject	Applied No./Date	Registered No./Date
1.CAPACITOR EXTERNAL ELECTRODE FORMING DEVICE, REDUCING AN AMOUNT OF PASTE CONSUMED BY EVAPORATION OR SCATTER	102007010312 Date of filing: 12.10.2007	1020090037676 A Date of publication of application: 16.04.2009
2.ICE MAKER	102003000481 Date of filing: 24.01.2003	1020040067644 A Date of publication of application: 30.07.2004
3.MASK CAPABLE OF TRANSCRIBING A PATTERN OF A HIGH RESOLUTION ON A SUBSTRATE, AN EXPOSURE APPARATUS INCLUDING THE SAME, AND AN EXPOSURE METHOD	102007010918 Date of filing: 29.10.2007	1020090043362 A Date of publication of application: 06.05.2009
4.PLASMA DISPLAY PANEL HAVING DISCHARGE SUSTAIN ELECTRODE WITH DUAL GAP AND METHOD FOR MANUFACTURING THE SAME	102003005161 Date of filing: 25.07.2003	1020040062383 A Date of publication of application: 07.07.2004
5.INKJET IMAGE FORMING APPARATUS AND A PRINTING METHOD USING THE SAME, CAPABLE OF VARYING AN INK EJECTION POSITION IN A MAIN SCANNING DIRECTION TO COMPENSATE AN INFERIOR NOZZLE AND IMPROVE PRINT RESOLUTION	102006010559 Date of filing: 30.10.2006	1020080038547 A (Date of publication of application: 07.05.2008
6.APPARATUS FOR INSPECTING TFT BOARD TO SHORTEN INTERVAL OF INSPECTION TIME	102005000887 Date of filing: 31.01.2005	1020060087946 A Date of publication of application: 03.08.2006
7.ORGANIC LIGHT EMITTING DEVICE AND A MANUFACTURING METHOD THEREOF, PARTICULARLY FOR REDUCING AN EFFECT OF A SURFACE STATE AND A THICKNESS OF A HOLE TRANSPORT LAYER ON THE ORGANIC LIGHT EMITTING DEVICE	102003009828 Date of filing: 27.12.2003	1020050067347 A Date of publication of application: 01.07.2005
8.THIN FILM TRANSISTOR ARRAY TEST APPARATUS TO SPEEDILY AND CONVENIENTLY TEST VARIOUS-SIZED THIN FILM TRANSISTOR ARRAYS IN ONE VACUUM CHAMBER	102005000643 Date of filing: 24.01.2005	1020060085536 A Date of publication of application: 27.07.2006
9.PHASE SHIFT MEMORY DEVICE USING VERTICAL TYPE PHASE SHIFT MATERIAL LAYER FOR REDUCING CONTACT REGION BETWEEN PHASE SHIFT MATERIAL LAYER AND UPPER ELECTRODE AND MANUFACTURING	102005001351 Date of filing: 18.02.2005	1020060092551 A Date of publication of application: 23.08.2006

METHOD THEREOF		
10. TIRE PRESSURE MONITORING SYSTEM FOR SIMPLIFYING ALGORITHM BUT IMPROVING SIGNAL PATH BY OPERATING ON IN OR OFF OUT OF A PREDETERMINED RANGE OF PRESSURE DIFFERENCE BETWEEN TWO CHAMBERS	102003009452 Date of filing: 22.12.2003	1020050063210 A Date of publication of application: 28.06.2005
<i>И другие</i>	<i>В настоящий момент подано всего</i>	<i>22- патента</i>